

Notice of References Cited	Application/Control No. 10/757,115	Applicant(s)/Patent Under Reexamination SMITH ET AL.	
	Examiner Hiep Nguyen	Art Unit 2816	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2007/0080723	04-2007	Lee et al.	327/112
	B US-			
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	E US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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